Microsemi Corporation - A54SX08A-PQG208I Datasheet

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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details	
Product Status	Obsolete
Number of LABs/CLBs	768
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	130
Number of Gates	12000
Voltage - Supply	2.25V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 85°C (TA)
Package / Case	208-BFQFP
Supplier Device Package	208-PQFP (28x28)
Purchase URL	https://www.e-xfl.com/product-detail/microsemi/a54sx08a-pqg208i

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Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

Temperature Grade Offering

Package	**A54SX08A**	**A54SX16A**	**A54SX32A**	**A54SX72A**
PQ208	C,I,A,M	C,I,A,M	C,I,A,M	C,I,A,M
TQ100	C,I,A,M	C,I,A,M	C,I,A,M	
TQ144	C,I,A,M	C,I,A,M	C,I,A,M	
TQ176			C,I,M	
BG329			C,I,M	
FG144	C,I,A,M	C,I,A,M	C,I,A,M	
FG256		C,I,A,M	C,I,A,M	C,I,A,M
FG484			C,I,M	C,I,A,M
CQ208			C,M,B	C,M,B
CQ256			C,M,B	C,M,B

Notes:

1. *C = Commercial*
2. *I = Industrial*
3. *A = Automotive*
4. *M = Military*
5. *B = MIL-STD-883 Class B*
6. *For more information regarding automotive products, refer to the* SX-A Automotive Family FPGAs *datasheet.*
7. *For more information regarding Mil-Temp and ceramic packages, refer to the* HiRel SX-A Family FPGAs *datasheet.*

Speed Grade and Temperature Grade Matrix

	F	**Std**	**–1**	**–2**	**–3**
Commercial	✓	✓	✓	✓	Discontinued
Industrial		✓	✓	✓	Discontinued
Automotive		✓			
Military		✓	✓		
MIL-STD-883B		✓	✓		

Notes:

1. *For more information regarding automotive products, refer to the* SX-A Automotive Family FPGAs *datasheet.*
2. *For more information regarding Mil-Temp and ceramic packages, refer to the* HiRel SX-A Family FPGAs *datasheet.*

Contact your Actel Sales representative for more information on availability.

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Clock Resources

Actel's high-drive routing structure provides three clock networks (Table 1-1). The first clock, called HCLK, is hardwired from the HCLK buffer to the clock select multiplexor (MUX) in each R-cell. HCLK cannot be connected to combinatorial logic. This provides a fast propagation path for the clock signal. If not used, this pin must be set as Low or High on the board. It must not be left floating. Figure 1-7 describes the clock circuit used for the constant load HCLK and the macros supported.

HCLK does not function until the fourth clock cycle each time the device is powered up to prevent false output levels due to any possible slow power-on-reset signal and fast start-up clock circuit. To activate HCLK from the first cycle, the TRST pin must be reserved in the Design software and the pin must be tied to GND on the board.

Two additional clocks (CLKA, CLKB) are global clocks that can be sourced from external pins or from internal logic signals within the SX-A device. CLKA and CLKB may be connected to sequential cells or to combinational logic. If CLKA or CLKB pins are not used or sourced from signals, these pins must be set as Low or High on the board. They must not be left floating. Figure 1-8 describes the CLKA and CLKB circuit used and the macros supported in SX-A devices with the exception of A54SX72A.

In addition, the A54SX72A device provides four quadrant clocks (QCLKA, QCLKB, QCLKC, and QCLKD—corresponding to bottom-left, bottom-right, top-left, and top-right locations on the die, respectively), which can be sourced from external pins or from internal logic signals within the device. Each of these clocks can individually drive up to an entire quadrant of the chip, or they can be grouped together to drive multiple quadrants (Figure 1-9 on page 1-6). QCLK pins can function as user I/O pins. If not used, the QCLK pins must be tied Low or High on the board and must not be left floating.

For more information on how to use quadrant clocks in the A54SX72A device, refer to the *Global Clock Networks in Actel's Antifuse Device*s and *Using A54SX72A and RT54SX72S Quadrant Clocks* application notes.

The CLKA, CLKB, and QCLK circuits for A54SX72A as well as the macros supported are shown in Figure 1-10 on page 1-6. Note that bidirectional clock buffers are only available in A54SX72A. For more information, refer to the "Pin Description" section on page 1-15.

Table 1-1 • **SX-A Clock Resources**

	A54SX08A	A54SX16A	A54SX32A	A54SX72A
Routed Clocks (CLKA, CLKB)	2	2	2	2
Hardwired Clocks (HCLK)	1	1	1	1
Quadrant Clocks (QCLKA, QCLKB, QCLKC, QCLKD)	0	0	0	4

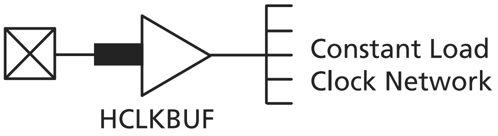


Figure 1-7 • **SX-A HCLK Clock Buffer**

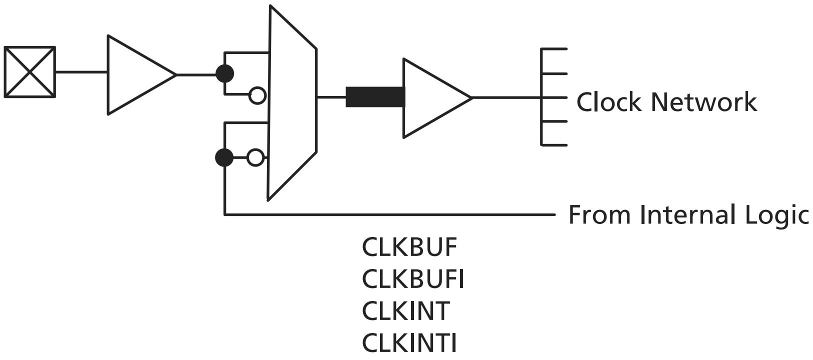


Figure 1-8 • **SX-A Routed Clock Buffer**

Power-Up/Down and Hot Swapping

SX-A I/Os are configured to be hot-swappable, with the exception of 3.3 V PCI. During power-up/down (or partial up/down), all I/Os are tristated. V_{CCA} and V_{CCI} do not have to be stable during power-up/down, and can be powered up/down in any order. When the SX-A device is plugged into an electrically active system, the device will not degrade the reliability of or cause damage to the host system. The device's output pins are driven to a high impedance state until normal chip operating conditions are reached. Table 1-4 summarizes the V_{CCA} voltage at which the I/Os behave according to the user's design for an SX-A device at room temperature for various ramp-up rates. The data reported assumes a linear ramp-up profile to 2.5 V. For more information on power-up and hot-swapping, refer to the application note, *Actel SX-A and RT54SX-S Devices in Hot-Swap and Cold-Sparing Applications*.

Table 1-2 • **I/O Features**

Function	**Description**
Input Buffer Threshold Selections	• 5 V: PCI, TTL • 3.3 V: PCI, LVTTL • 2.5 V: LVCMOS2 (commercial only)
Flexible Output Driver	• 5 V: PCI, TTL • 3.3 V: PCI, LVTTL • 2.5 V: LVCMOS2 (commercial only)
Output Buffer	"Hot-Swap" Capability (3.3 V PCI is not hot swappable) • I/O on an unpowered device does not sink current • Can be used for "cold-sparing" Selectable on an individual I/O basis Individually selectable slew rate; high slew or low slew (The default is high slew rate). The slew is only affected on the falling edge of an output. Rising edges of outputs are not affected.
Power-Up	Individually selectable pull-ups and pull-downs during power-up (default is to power-up in tristate) Enables deterministic power-up of device V_{CCA} and V_{CCI} can be powered in any order

Table 1-3 • **I/O Characteristics for All I/O Configurations**

	Hot Swappable	**Slew Rate Control**	**Power-Up Resistor**
TTL, LVTTL, LVCMOS2	Yes	Yes. Only affects falling edges of outputs	Pull-up or pull-down
3.3 V PCI	No	No. High slew rate only	Pull-up or pull-down
5 V PCI	Yes	No. High slew rate only	Pull-up or pull-down

Table 1-4 • **Power-Up Time at which I/Os Become Active**

Supply Ramp Rate	**0.25 V/µs**	**0.025 V/µs**	**5 V/ms**	**2.5 V/ms**	**0.5 V/ms**	**0.25 V/ms**	**0.1 V/ms**	**0.025 V/ms**
Units	**µs**	**µs**	**ms**	**ms**	**ms**	**ms**	**ms**	**ms**
A54SX08A	10	96	0.34	0.65	2.7	5.4	12.9	50.8
A54SX16A	10	100	0.36	0.62	2.5	4.7	11.0	41.6
A54SX32A	10	100	0.46	0.74	2.8	5.2	12.1	47.2
A54SX72A	10	100	0.41	0.67	2.6	5.0	12.1	47.2

Boundary-Scan Testing (BST)

All SX-A devices are IEEE 1149.1 compliant and offer superior diagnostic and testing capabilities by providing Boundary Scan Testing (BST) and probing capabilities. The BST function is controlled through the special JTAG pins (TMS, TDI, TCK, TDO, and TRST). The functionality of the JTAG pins is defined by two available modes: Dedicated and Flexible. TMS cannot be employed as a user I/O in either mode.

Dedicated Mode

In Dedicated mode, all JTAG pins are reserved for BST; designers cannot use them as regular I/Os. An internal pull-up resistor is automatically enabled on both TMS and TDI pins, and the TMS pin will function as defined in the IEEE 1149.1 (JTAG) specification.

To select Dedicated mode, the user must reserve the JTAG pins in Actel's Designer software. Reserve the JTAG pins by checking the **Reserve JTAG** box in the Device Selection Wizard (Figure 1-12).

The default for the software is Flexible mode; all boxes are unchecked. Table 1-5 lists the definitions of the options in the Device Selection Wizard.

Figure 1-12 • **Device Selection Wizard**

Table 1-5 • **Reserve Pin Definitions**

Pin	Function
Reserve JTAG	Keeps pins from being used and changes the behavior of JTAG pins (no pull-up on TMS)
Reserve JTAG Test Reset	Regular I/O or JTAG reset with an internal pull-up
Reserve Probe	Keeps pins from being used or regular I/O

Flexible Mode

In Flexible mode, TDI, TCK, and TDO may be employed as either user I/Os or as JTAG input pins. The internal resistors on the TMS and TDI pins are not present in flexible JTAG mode.

To select the Flexible mode, uncheck the **Reserve JTAG** box in the Device Selection Wizard dialog in the Actel Designer software. In Flexible mode, TDI, TCK, and TDO pins may function as user I/Os or BST pins. The functionality is controlled by the BST Test Access Port (TAP) controller. The TAP controller receives two control inputs, TMS and TCK. Upon power-up, the TAP controller enters the Test-Logic-Reset state. In this state, TDI, TCK, and TDO function as user I/Os. The TDI, TCK, and TDO are transformed from user I/Os into BST pins when a rising edge on TCK is detected while TMS is at logic low. To return to Test-Logic Reset state, TMS must be high for at least five TCK cycles. **An external 10 k pull-up resistor to V_{CCI} should be placed on the TMS pin to pull it High by default.**

Table 1-6 describes the different configuration requirements of BST pins and their functionality in different modes.

Table 1-6 • **Boundary-Scan Pin Configurations and Functions**

Mode	Designer "Reserve JTAG" Selection	TAP Controller State
Dedicated (JTAG)	Checked	Any
Flexible (User I/O)	Unchecked	Test-Logic-Reset
Flexible (JTAG)	Unchecked	Any EXCEPT Test-Logic-Reset

TRST Pin

The TRST pin functions as a dedicated Boundary-Scan Reset pin when the **Reserve JTAG Test Reset** option is selected as shown in Figure 1-12. An internal pull-up resistor is permanently enabled on the TRST pin in this mode. Actel recommends connecting this pin to ground in normal operation to keep the JTAG state controller in the Test-Logic-Reset state. When JTAG is being used, it can be left floating or can be driven high.

When the **Reserve JTAG Test Reset** option is not selected, this pin will function as a regular I/O. If unused as an I/O in the design, it will be configured as a tristated output.

Probing Capabilities

SX-A devices also provide an internal probing capability that is accessed with the JTAG pins. The Silicon Explorer II diagnostic hardware is used to control the TDI, TCK, TMS, and TDO pins to select the desired nets for debugging. The user assigns the selected internal nets in Actel Silicon Explorer II software to the PRA/PRB output pins for observation. Silicon Explorer II automatically places the device into JTAG mode. However, probing functionality is only activated when the TRST pin is driven high or left floating, allowing the internal pull-up resistor to pull TRST High. If the TRST pin is held Low, the TAP controller remains in the Test-Logic-Reset state so no probing can be performed. However, the user must drive the TRST pin High or allow the internal pull-up resistor to pull TRST High.

When selecting the **Reserve Probe Pin** box as shown in Figure 1-12 on page 1-9, direct the layout tool to reserve the PRA and PRB pins as dedicated outputs for probing. This **Reserve** option is merely a guideline. If the designer assigns user I/Os to the PRA and PRB pins and selects the **Reserve Probe Pin** option, Designer Layout will override the **Reserve Probe Pin** option and place the user I/Os on those pins.

To allow probing capabilities, the security fuse must not be programmed. Programming the security fuse disables the JTAG and probe circuitry. Table 1-9 summarizes the possible device configurations for probing once the device leaves the Test-Logic-Reset JTAG state.

Table 1-9 • **Device Configuration Options for Probe Capability (TRST Pin Reserved)**

JTAG Mode	**TRST**[1]	**Security Fuse Programmed**	**PRA, PRB**[2]	**TDI, TCK, TDO**[2]
Dedicated	Low	No	User I/O[3]	JTAG Disabled
	High	No	Probe Circuit Outputs	JTAG I/O
Flexible	Low	No	User I/O[3]	User I/O[3]
	High	No	Probe Circuit Outputs	JTAG I/O
		Yes	Probe Circuit Secured	Probe Circuit Secured

Notes:

1. *If the TRST pin is not reserved, the device behaves according to TRST = High as described in the table.*
2. *Avoid using the TDI, TCK, TDO, PRA, and PRB pins as input or bidirectional ports. Since these pins are active during probing, input signals will not pass through these pins and may cause contention.*
3. *If no user signal is assigned to these pins, they will behave as unused I/Os in this mode. Unused pins are automatically tristated by the Designer software.*

Table 2-8 • **AC Specifications (5 V PCI Operation)**

Symbol	Parameter	Condition	Min.	Max.	Units
$I_{OH(AC)}$	Switching Current High	$0 < V_{OUT} \le 1.4$ [1]	–44	–	mA
		$1.4 \le V_{OUT} < 2.4$ [1, 2]	$(-44 + (V_{OUT} - 1.4)/0.024)$	–	mA
		$3.1 < V_{OUT} < V_{CCI}$ [1, 3]	–	EQ 2-1 on page 2-5	–
	(Test Point)	$V_{OUT} = 3.1$ [3]	–	–142	mA
$I_{OL(AC)}$	Switching Current Low	$V_{OUT} \ge 2.2$ [1]	95	–	mA
		$2.2 > V_{OUT} > 0.55$ [1]	$(V_{OUT}/0.023)$	–	mA
		$0.71 > V_{OUT} > 0$ [1, 3]	–	EQ 2-2 on page 2-5	–
	(Test Point)	$V_{OUT} = 0.71$ [3]	–	206	mA
I_{CL}	Low Clamp Current	$-5 < V_{IN} \le -1$	$-25 + (V_{IN} + 1)/0.015$	–	mA
$slew_R$	Output Rise Slew Rate	0.4 V to 2.4 V load [4]	1	5	V/ns
$slew_F$	Output Fall Slew Rate	2.4 V to 0.4 V load [4]	1	5	V/ns

Notes:

1. *Refer to the V/I curves in Figure 2-1 on page 2-5. Switching current characteristics for REQ# and GNT# are permitted to be one half of that specified here; i.e., half size output drivers may be used on these signals. This specification does not apply to CLK and RST#, which are system outputs. "Switching Current High" specifications are not relevant to SERR#, INTA#, INTB#, INTC#, and INTD#, which are open drain outputs.*
2. *Note that this segment of the minimum current curve is drawn from the AC drive point directly to the DC drive point rather than toward the voltage rail (as is done in the pull-down curve). This difference is intended to allow for an optional N-channel pull-up.*
3. *Maximum current requirements must be met as drivers pull beyond the last step voltage. Equations defining these maximums (A and B) are provided with the respective diagrams in Figure 2-1 on page 2-5. The equation defined maximum should be met by design. In order to facilitate component testing, a maximum current test point is defined for each side of the output driver.*
4. *This parameter is to be interpreted as the cumulative edge rate across the specified range, rather than the instantaneous rate at any point within the transition range. The specified load (diagram below) is optional; i.e., the designer may elect to meet this parameter with an unloaded output per revision 2.0 of the PCI Local Bus Specification. However, adherence to both maximum and minimum parameters is now required (the maximum is no longer simply a guideline). Since adherence to the maximum slew rate was not required prior to revision 2.1 of the specification, there may be components in the market for some time that have faster edge rates; therefore, motherboard designers must bear in mind that rise and fall times faster than this specification could occur and should ensure that signal integrity modeling accounts for this. Rise slew rate does not apply to open drain outputs.*

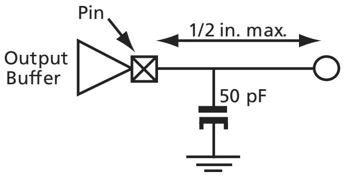
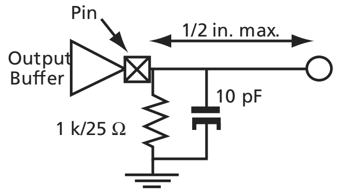


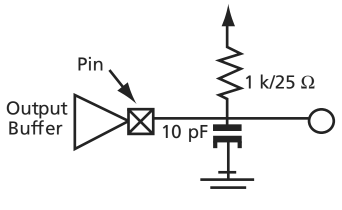
Table 2-10 • **AC Specifications (3.3 V PCI Operation)**

Symbol	**Parameter**	**Condition**	**Min.**	**Max.**	**Units**
$I_{OH(AC)}$	Switching Current High	$0 < V_{OUT} \leq 0.3V_{CCI}$ [1]	$-12V_{CCI}$	–	mA
		$0.3V_{CCI} \leq V_{OUT} < 0.9V_{CCI}$ [1]	$(-17.1(V_{CCI} - V_{OUT}))$	–	mA
		$0.7V_{CCI} < V_{OUT} < V_{CCI}$ [1, 2]	–	EQ 2-3 on page 2-7	–
	(Test Point)	$V_{OUT} = 0.7V_{CC}$ [2]	–	$-32V_{CCI}$	mA
$I_{OL(AC)}$	Switching Current Low	$V_{CCI} > V_{OUT} \geq 0.6V_{CCI}$ [1]	$16V_{CCI}$	–	mA
		$0.6V_{CCI} > V_{OUT} > 0.1V_{CCI}$ [1]	$(26.7V_{OUT})$	–	mA
		$0.18V_{CCI} > V_{OUT} > 0$ [1, 2]	–	EQ 2-4 on page 2-7	–
	(Test Point)	$V_{OUT} = 0.18V_{CC}$ [2]	–	$38V_{CCI}$	mA
I_{CL}	Low Clamp Current	$-3 < V_{IN} \leq -1$	$-25 + (V_{IN} + 1)/0.015$	–	mA
I_{CH}	High Clamp Current	$V_{CCI} + 4 > V_{IN} \geq V_{CCI} + 1$	$25 + (V_{IN} - V_{CCI} - 1)/0.015$	–	mA
$slew_R$	Output Rise Slew Rate	$0.2V_{CCI}$ - $0.6V_{CCI}$ load [3]	1	4	V/ns
$slew_F$	Output Fall Slew Rate	$0.6V_{CCI}$ - $0.2V_{CCI}$ load [3]	1	4	V/ns

Notes:

1. *Refer to the V/I curves in Figure 2-2 on page 2-7. Switching current characteristics for REQ# and GNT# are permitted to be one half of that specified here; i.e., half size output drivers may be used on these signals. This specification does not apply to CLK and RST#, which are system outputs. "Switching Current High" specifications are not relevant to SERR#, INTA#, INTB#, INTC#, and INTD#, which are open drain outputs.*
2. *Maximum current requirements must be met as drivers pull beyond the last step voltage. Equations defining these maximums (C and D) are provided with the respective diagrams in Figure 2-2 on page 2-7. The equation defined maximum should be met by design. In order to facilitate component testing, a maximum current test point is defined for each side of the output driver.*
3. *This parameter is to be interpreted as the cumulative edge rate across the specified range, rather than the instantaneous rate at any point within the transition range. The specified load (diagram below) is optional; i.e., the designer may elect to meet this parameter with an unloaded output per the latest revision of the PCI Local Bus Specification. However, adherence to both maximum and minimum parameters is required (the maximum is no longer simply a guideline). Rise slew rate does not apply to open drain outputs.*





Thermal Characteristics

Introduction

The temperature variable in Actel Designer software refers to the junction temperature, not the ambient, case, or board temperatures. This is an important distinction because dynamic and static power consumption will cause the chip's junction to be higher than the ambient, case, or board temperatures. EQ 2-9 and EQ 2-10 give the relationship between thermal resistance, temperature gradient and power.

$$\theta_{JA} = \frac{T_J - T_A}{P}$$

EQ 2-9

$$\theta_{JA} = \frac{T_C - T_A}{P}$$

EQ 2-10

Where:

θ_{JA} = Junction-to-air thermal resistance
θ_{JC} = Junction-to-case thermal resistance
T_J = Junction temperature
T_A = Ambient temperature
T_C = Ambient temperature
P = total power dissipated by the device

Table 2-12 • **Package Thermal Characteristics**

Package Type	Pin Count	θ_{JC}	θ_{JA} Still Air	θ_{JA} 1.0 m/s 200 ft./min.	θ_{JA} 2.5 m/s 500 ft./min.	Units
Thin Quad Flat Pack (TQFP)	100	14	33.5	27.4	25	°C/W
Thin Quad Flat Pack (TQFP)	144	11	33.5	28	25.7	°C/W
Thin Quad Flat Pack (TQFP)	176	11	24.7	19.9	18	°C/W
Plastic Quad Flat Pack (PQFP)[1]	208	8	26.1	22.5	20.8	°C/W
Plastic Quad Flat Pack (PQFP) with Heat Spreader[2]	208	3.8	16.2	13.3	11.9	°C/W
Plastic Ball Grid Array (PBGA)	329	3	17.1	13.8	12.8	°C/W
Fine Pitch Ball Grid Array (FBGA)	144	3.8	26.9	22.9	21.5	°C/W
Fine Pitch Ball Grid Array (FBGA)	256	3.8	26.6	22.8	21.5	°C/W
Fine Pitch Ball Grid Array (FBGA)	484	3.2	18	14.7	13.6	°C/W

Notes:

1. *The A54SX08A PQ208 has no heat spreader.*
2. *The SX-A PQ208 package has a heat spreader for A54SX16A, A54SX32A, and A54SX72A.*

Table 2-14 • **A54SX08A Timing Characteristics (Continued)**
(Worst-Case Commercial Conditions, V_{CCA} = 2.25 V, V_{CCI} = 3.0 V, T_J = 70°C)

Parameter	Description	–2 Speed Min.	–2 Speed Max.	–1 Speed Min.	–1 Speed Max.	Std. Speed Min.	Std. Speed Max.	–F Speed Min.	–F Speed Max.	Units
t_{INYH}	Input Data Pad to Y High 5 V PCI		0.5		0.6		0.7		0.9	ns
t_{INYL}	Input Data Pad to Y Low 5 V PCI		0.8		0.9		1.1		1.5	ns
t_{INYH}	Input Data Pad to Y High 5 V TTL		0.5		0.6		0.7		0.9	ns
t_{INYL}	Input Data Pad to Y Low 5 V TTL		0.8		0.9		1.1		1.5	ns
Input Module Predicted Routing Delays[2]										
t_{IRD1}	FO = 1 Routing Delay		0.3		0.3		0.4		0.6	ns
t_{IRD2}	FO = 2 Routing Delay		0.5		0.5		0.6		0.8	ns
t_{IRD3}	FO = 3 Routing Delay		0.6		0.7		0.8		1.1	ns
t_{IRD4}	FO = 4 Routing Delay		0.8		0.9		1		1.4	ns
t_{IRD8}	FO = 8 Routing Delay		1.4		1.5		1.8		2.5	ns
t_{IRD12}	FO = 12 Routing Delay		2		2.2		2.6		3.6	ns

Notes:

1. *For dual-module macros, use t_{PD} + t_{RD1} + t_{PDn} , t_{RCO} + t_{RD1} + t_{PDn} , or t_{PD1} + t_{RD1} + t_{SUD} , whichever is appropriate.*
2. *Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.*

Table 2-16 • **A54SX08A Timing Characteristics**
(Worst-Case Commercial Conditions V_{CCA} = 2.25 V, V_{CCI} = 3.0 V, T_J = 70°C)

		–2 Speed		–1 Speed		Std. Speed		–F Speed		
Parameter	**Description**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Units**
Dedicated (Hardwired) Array Clock Networks										
t_{HCKH}	Input Low to High (Pad to R-cell Input)		1.3		1.5		1.7		2.6	ns
t_{HCKL}	Input High to Low (Pad to R-cell Input)		1.1		1.3		1.5		2.2	ns
t_{HPWH}	Minimum Pulse Width High	1.6		1.8		2.1		2.9		ns
t_{HPWL}	Minimum Pulse Width Low	1.6		1.8		2.1		2.9		ns
t_{HCKSW}	Maximum Skew		0.4		0.5		0.5		0.8	ns
t_{HP}	Minimum Period	3.2		3.6		4.2		5.8		ns
f_{HMAX}	Maximum Frequency		313		278		238		172	MHz
Routed Array Clock Networks										
t_{RCKH}	Input Low to High (Light Load) (Pad to R-cell Input)		0.8		0.9		1.1		1.5	ns
t_{RCKL}	Input High to Low (Light Load) (Pad to R-cell Input)		1.1		1.2		1.4		2	ns
t_{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		0.8		0.9		1.1		1.5	ns
t_{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)		1.1		1.2		1.4		2	ns
t_{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		1.1		1.2		1.4		1.9	ns
t_{RCKL}	Input High to Low (100% Load) (Pad to R-cell Input)		1.2		1.3		1.6		2.2	ns
t_{RPWH}	Minimum Pulse Width High	1.6		1.8		2.1		2.9		ns
t_{RPWL}	Minimum Pulse Width Low	1.6		1.8		2.1		2.9		ns
t_{RCKSW}	Maximum Skew (Light Load)		0.7		0.8		0.9		1.3	ns
t_{RCKSW}	Maximum Skew (50% Load)		0.7		0.8		0.9		1.3	ns
t_{RCKSW}	Maximum Skew (100% Load)		0.8		0.9		1.1		1.5	ns

Table 2-20 • **A54SX08A Timing Characteristics (Worst-Case Commercial Conditions V_{CCA} = 2.25 V, V_{CCI} = 4.75 V, T_J = 70°C)**

Parameter	Description	–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
5 V PCI Output Module Timing[1]										
t_{DLH}	Data-to-Pad Low to High		2.4		2.8		3.2		4.5	ns
t_{DHL}	Data-to-Pad High to Low		3.2		3.6		4.2		5.9	ns
t_{ENZL}	Enable-to-Pad, Z to L		1.5		1.7		2.0		2.8	ns
t_{ENZH}	Enable-to-Pad, Z to H		2.4		2.8		3.2		4.5	ns
t_{ENLZ}	Enable-to-Pad, L to Z		3.5		3.9		4.6		6.4	ns
t_{ENHZ}	Enable-to-Pad, H to Z		3.2		3.6		4.2		5.9	ns
d_{TLH}[2]	Delta Low to High		0.016		0.02		0.022		0.032	ns/pF
d_{THL}[2]	Delta High to Low		0.03		0.032		0.04		0.052	ns/pF
5 V TTL Output Module Timing[3]										
t_{DLH}	Data-to-Pad Low to High		2.4		2.8		3.2		4.5	ns
t_{DHL}	Data-to-Pad High to Low		3.2		3.6		4.2		5.9	ns
t_{DHLS}	Data-to-Pad High to Low—low slew		7.6		8.6		10.1		14.2	ns
t_{ENZL}	Enable-to-Pad, Z to L		2.4		2.7		3.2		4.5	ns
t_{ENZLS}	Enable-to-Pad, Z to L—low slew		8.4		9.5		11.0		15.4	ns
t_{ENZH}	Enable-to-Pad, Z to H		2.4		2.8		3.2		4.5	ns
t_{ENLZ}	Enable-to-Pad, L to Z		4.2		4.7		5.6		7.8	ns
t_{ENHZ}	Enable-to-Pad, H to Z		3.2		3.6		4.2		5.9	ns
d_{TLH}	Delta Low to High		0.017		0.017		0.023		0.031	ns/pF
d_{THL}	Delta High to Low		0.029		0.031		0.037		0.051	ns/pF
d_{THLS}	Delta High to Low—low slew		0.046		0.057		0.066		0.089	ns/pF

Notes:

1. *Delays based on 50 pF loading.*
2. *To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:*
   Slew Rate [V/ns] = $(0.1*V_{CCI} – 0.9*V_{CCI})/ (C_{load} * d_{T[LH|HL|HLS]})$
   where C_{load} is the load capacitance driven by the I/O in pF
   $d_{T[LH|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.
3. *Delays based on 35 pF loading.*

Table 2-23 • **A54SX16A Timing Characteristics**
(Worst-Case Commercial Conditions V_{CCA} = 2.25 V, V_{CCI} = 3.0 V, T_J = 70°C)

Parameter	Description	–3 Speed*		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Dedicated (Hardwired) Array Clock Networks												
t_{HCKH}	Input Low to High (Pad to R-cell Input)		1.2		1.4		1.6		1.8		2.8	ns
t_{HCKL}	Input High to Low (Pad to R-cell Input)		1.0		1.1		1.3		1.5		2.2	ns
t_{HPWH}	Minimum Pulse Width High	1.4		1.7		1.9		2.2		3.0		ns
t_{HPWL}	Minimum Pulse Width Low	1.4		1.7		1.9		2.2		3.0		ns
t_{HCKSW}	Maximum Skew		0.3		0.3		0.4		0.4		0.6	ns
t_{HP}	Minimum Period	2.8		3.4		3.8		4.4		6.0		ns
f_{HMAX}	Maximum Frequency		357		294		263		227		167	MHz
Routed Array Clock Networks												
t_{RCKH}	Input Low to High (Light Load) (Pad to R-cell Input)		1.0		1.2		1.3		1.5		2.1	ns
t_{RCKL}	Input High to Low (Light Load) (Pad to R-cell Input)		1.1		1.3		1.5		1.7		2.4	ns
t_{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		1.1		1.3		1.4		1.7		2.3	ns
t_{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)		1.1		1.3		1.5		1.7		2.4	ns
t_{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		1.3		1.5		1.7		2.0		2.7	ns
t_{RCKL}	Input High to Low (100% Load) (Pad to R-cell Input)		1.3		1.5		1.7		2.0		2.8	ns
t_{RPWH}	Minimum Pulse Width High	1.4		1.7		1.9		2.2		3.0		ns
t_{RPWL}	Minimum Pulse Width Low	1.4		1.7		1.9		2.2		3.0		ns
t_{RCKSW}	Maximum Skew (Light Load)		0.8		0.9		1.0		1.2		1.7	ns
t_{RCKSW}	Maximum Skew (50% Load)		0.8		0.9		1.0		1.2		1.7	ns
t_{RCKSW}	Maximum Skew (100% Load)		1.0		1.1		1.3		1.5		2.1	ns

Note: **All –3 speed grades have been discontinued.*

Table 2-27 • **A54SX16A Timing Characteristics (Worst-Case Commercial Conditions V_{CCA} = 2.25 V, V_{CCI} = 4.75 V, T_J = 70°C)**

Parameter	Description	–3 Speed[1]		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
5 V PCI Output Module Timing[2]												
t_{DLH}	Data-to-Pad Low to High		2.2		2.5		2.8		3.3		4.6	ns
t_{DHL}	Data-to-Pad High to Low		2.8		3.2		3.6		4.2		5.9	ns
t_{ENZL}	Enable-to-Pad, Z to L		1.3		1.5		1.7		2.0		2.8	ns
t_{ENZH}	Enable-to-Pad, Z to H		2.2		2.5		2.8		3.3		4.6	ns
t_{ENLZ}	Enable-to-Pad, L to Z		3.0		3.5		3.9		4.6		6.4	ns
t_{ENHZ}	Enable-to-Pad, H to Z		2.8		3.2		3.6		4.2		5.9	ns
d_{TLH}[3]	Delta Low to High		0.016		0.016		0.02		0.022		0.032	ns/pF
d_{THL}[3]	Delta High to Low		0.026		0.03		0.032		0.04		0.052	ns/pF
5 V TTL Output Module Timing[4]												
t_{DLH}	Data-to-Pad Low to High		2.2		2.5		2.8		3.3		4.6	ns
t_{DHL}	Data-to-Pad High to Low		2.8		3.2		3.6		4.2		5.9	ns
t_{DHLS}	Data-to-Pad High to Low—low slew		6.7		7.7		8.7		10.2		14.3	ns
t_{ENZL}	Enable-to-Pad, Z to L		2.1		2.4		2.7		3.2		4.5	ns
t_{ENZLS}	Enable-to-Pad, Z to L—low slew		7.4		8.4		9.5		11.0		15.4	ns
t_{ENZH}	Enable-to-Pad, Z to H		1.9		2.2		2.5		2.9		4.1	ns
t_{ENLZ}	Enable-to-Pad, L to Z		3.6		4.2		4.7		5.6		7.8	ns
t_{ENHZ}	Enable-to-Pad, H to Z		2.5		2.9		3.3		3.9		5.4	ns
d_{TLH}[3]	Delta Low to High		0.014		0.017		0.017		0.023		0.031	ns/pF
d_{THL}[3]	Delta High to Low		0.023		0.029		0.031		0.037		0.051	ns/pF
d_{THLS}[3]	Delta High to Low—low slew		0.043		0.046		0.057		0.066		0.089	ns/pF

Notes:

1. *All –3 speed grades have been discontinued.*
2. *Delays based on 50 pF loading.*
3. *To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:*
   Slew Rate [V/ns] = $(0.1 * V_{CCI} – 0.9 * V_{CCI}) / (C_{load} * d_{T[LH|HL|HLS]})$
   where C_{load} is the load capacitance driven by the I/O in pF
   $d_{T[LH|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.
4. *Delays based on 35 pF loading.*

Table 2-28 • **A54SX32A Timing Characteristics**
(Worst-Case Commercial Conditions, V_{CCA} = 2.25 V, V_{CCI} = 3.0 V, T_J = 70°C)

Parameter	Description	–3 Speed[1]		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
C-Cell Propagation Delays[2]												
t_{PD}	Internal Array Module		0.8		0.9		1.1		1.2		1.7	ns
Predicted Routing Delays[3]												
t_{DC}	FO = 1 Routing Delay, Direct Connect		0.1		0.1		0.1		0.1		0.1	ns
t_{FC}	FO = 1 Routing Delay, Fast Connect		0.3		0.3		0.3		0.4		0.6	ns
t_{RD1}	FO = 1 Routing Delay		0.3		0.3		0.4		0.5		0.6	ns
t_{RD2}	FO = 2 Routing Delay		0.4		0.5		0.5		0.6		0.8	ns
t_{RD3}	FO = 3 Routing Delay		0.5		0.6		0.7		0.8		1.1	ns
t_{RD4}	FO = 4 Routing Delay		0.7		0.8		0.9		1.0		1.4	ns
t_{RD8}	FO = 8 Routing Delay		1.2		1.4		1.5		1.8		2.5	ns
t_{RD12}	FO = 12 Routing Delay		1.7		2.0		2.2		2.6		3.6	ns
R-Cell Timing												
t_{RCO}	Sequential Clock-to-Q		0.6		0.7		0.8		0.9		1.3	ns
t_{CLR}	Asynchronous Clear-to-Q		0.5		0.6		0.6		0.8		1.0	ns
t_{PRESET}	Asynchronous Preset-to-Q		0.6		0.7		0.7		0.9		1.2	ns
t_{SUD}	Flip-Flop Data Input Set-Up	0.6		0.7		0.8		0.9		1.2		ns
t_{HD}	Flip-Flop Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{WASYN}	Asynchronous Pulse Width	1.2		1.4		1.5		1.8		2.5		ns
$t_{RECASYN}$	Asynchronous Recovery Time	0.3		0.4		0.4		0.5		0.7		ns
t_{HASYN}	Asynchronous Removal Time	0.3		0.3		0.3		0.4		0.6		ns
t_{MPW}	Clock Pulse Width	1.4		1.6		1.8		2.1		2.9		ns
Input Module Propagation Delays												
t_{INYH}	Input Data Pad to Y High 2.5 V LVCMOS		0.6		0.7		0.8		0.9		1.2	ns
t_{INYL}	Input Data Pad to Y Low 2.5 V LVCMOS		1.2		1.3		1.5		1.8		2.5	ns
t_{INYH}	Input Data Pad to Y High 3.3 V PCI		0.5		0.6		0.6		0.7		1.0	ns
t_{INYL}	Input Data Pad to Y Low 3.3 V PCI		0.6		0.7		0.8		0.9		1.3	ns
t_{INYH}	Input Data Pad to Y High 3.3 V LVTTL		0.8		0.9		1.0		1.2		1.6	ns
t_{INYL}	Input Data Pad to Y Low 3.3 V LVTTL		1.4		1.6		1.8		2.2		3.0	ns

Notes:

1. *All –3 speed grades have been discontinued.*
2. *For dual-module macros, use* $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, *or* $t_{PD1} + t_{RD1} + t_{SUD}$, *whichever is appropriate.*
3. *Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.*

Table 2-31 • **A54SX32A Timing Characteristics (Worst-Case Commercial Conditions V_{CCA} = 2.25 V, V_{CCI} = 4.75 V, T_J = 70°C)**

Parameter	**Description**	**–3 Speed***		**–2 Speed**		**–1 Speed**		**Std. Speed**		**–F Speed**		**Units**
		Min.	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	
Dedicated (Hardwired) Array Clock Networks												
t_{HCKH}	Input Low to High (Pad to R-cell Input)		1.7		1.9		2.2		2.6		4.0	ns
t_{HCKL}	Input High to Low (Pad to R-cell Input)		1.7		2.0		2.2		2.6		4.0	ns
t_{HPWH}	Minimum Pulse Width High	1.4		1.6		1.8		2.1		2.9		ns
t_{HPWL}	Minimum Pulse Width Low	1.4		1.6		1.8		2.1		2.9		ns
t_{HCKSW}	Maximum Skew		0.6		0.6		0.7		0.8		1.3	ns
t_{HP}	Minimum Period	2.8		3.2		3.6		4.2		5.8		ns
f_{HMAX}	Maximum Frequency		357		313		278		238		172	MHz
Routed Array Clock Networks												
t_{RCKH}	Input Low to High (Light Load) (Pad to R-cell Input)		2.2		2.5		2.8		3.3		4.7	ns
t_{RCKL}	Input High to Low (Light Load) (Pad to R-cell Input)		2.1		2.5		2.8		3.3		4.5	ns
t_{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		2.4		2.7		3.1		3.6		5.1	ns
t_{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)		2.2		2.6		2.9		3.4		4.7	ns
t_{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		2.5		2.8		3.2		3.8		5.3	ns
t_{RCKL}	Input High to Low (100% Load) (Pad to R-cell Input)		2.4		2.8		3.1		3.7		5.2	ns
t_{RPWH}	Minimum Pulse Width High	1.4		1.6		1.8		2.1		2.9		ns
t_{RPWL}	Minimum Pulse Width Low	1.4		1.6		1.8		2.1		2.9		ns
t_{RCKSW}	Maximum Skew (Light Load)		1.0		1.1		1.3		1.5		2.1	ns
t_{RCKSW}	Maximum Skew (50% Load)		1.0		1.1		1.3		1.5		2.1	ns
t_{RCKSW}	Maximum Skew (100% Load)		1.0		1.1		1.3		1.5		2.1	ns

Note: **All –3 speed grades have been discontinued.*

144-Pin TQFP			
Pin Number	**A54SX08A Function**	**A54SX16A Function**	**A54SX32A Function**
1	GND	GND	GND
2	TDI, I/O	TDI, I/O	TDI, I/O
3	I/O	I/O	I/O
4	I/O	I/O	I/O
5	I/O	I/O	I/O
6	I/O	I/O	I/O
7	I/O	I/O	I/O
8	I/O	I/O	I/O
9	TMS	TMS	TMS
10	V_{CCI}	V_{CCI}	V_{CCI}
11	GND	GND	GND
12	I/O	I/O	I/O
13	I/O	I/O	I/O
14	I/O	I/O	I/O
15	I/O	I/O	I/O
16	I/O	I/O	I/O
17	I/O	I/O	I/O
18	I/O	I/O	I/O
19	NC	NC	NC
20	V_{CCA}	V_{CCA}	V_{CCA}
21	I/O	I/O	I/O
22	TRST, I/O	TRST, I/O	TRST, I/O
23	I/O	I/O	I/O
24	I/O	I/O	I/O
25	I/O	I/O	I/O
26	I/O	I/O	I/O
27	I/O	I/O	I/O
28	GND	GND	GND
29	V_{CCI}	V_{CCI}	V_{CCI}
30	V_{CCA}	V_{CCA}	V_{CCA}
31	I/O	I/O	I/O
32	I/O	I/O	I/O
33	I/O	I/O	I/O
34	I/O	I/O	I/O
35	I/O	I/O	I/O
36	GND	GND	GND
37	I/O	I/O	I/O

144-Pin TQFP			
Pin Number	**A54SX08A Function**	**A54SX16A Function**	**A54SX32A Function**
38	I/O	I/O	I/O
39	I/O	I/O	I/O
40	I/O	I/O	I/O
41	I/O	I/O	I/O
42	I/O	I/O	I/O
43	I/O	I/O	I/O
44	V_{CCI}	V_{CCI}	V_{CCI}
45	I/O	I/O	I/O
46	I/O	I/O	I/O
47	I/O	I/O	I/O
48	I/O	I/O	I/O
49	I/O	I/O	I/O
50	I/O	I/O	I/O
51	I/O	I/O	I/O
52	I/O	I/O	I/O
53	I/O	I/O	I/O
54	PRB, I/O	PRB, I/O	PRB, I/O
55	I/O	I/O	I/O
56	V_{CCA}	V_{CCA}	V_{CCA}
57	GND	GND	GND
58	NC	NC	NC
59	I/O	I/O	I/O
60	HCLK	HCLK	HCLK
61	I/O	I/O	I/O
62	I/O	I/O	I/O
63	I/O	I/O	I/O
64	I/O	I/O	I/O
65	I/O	I/O	I/O
66	I/O	I/O	I/O
67	I/O	I/O	I/O
68	V_{CCI}	V_{CCI}	V_{CCI}
69	I/O	I/O	I/O
70	I/O	I/O	I/O
71	TDO, I/O	TDO, I/O	TDO, I/O
72	I/O	I/O	I/O
73	GND	GND	GND
74	I/O	I/O	I/O

329-Pin PBGA

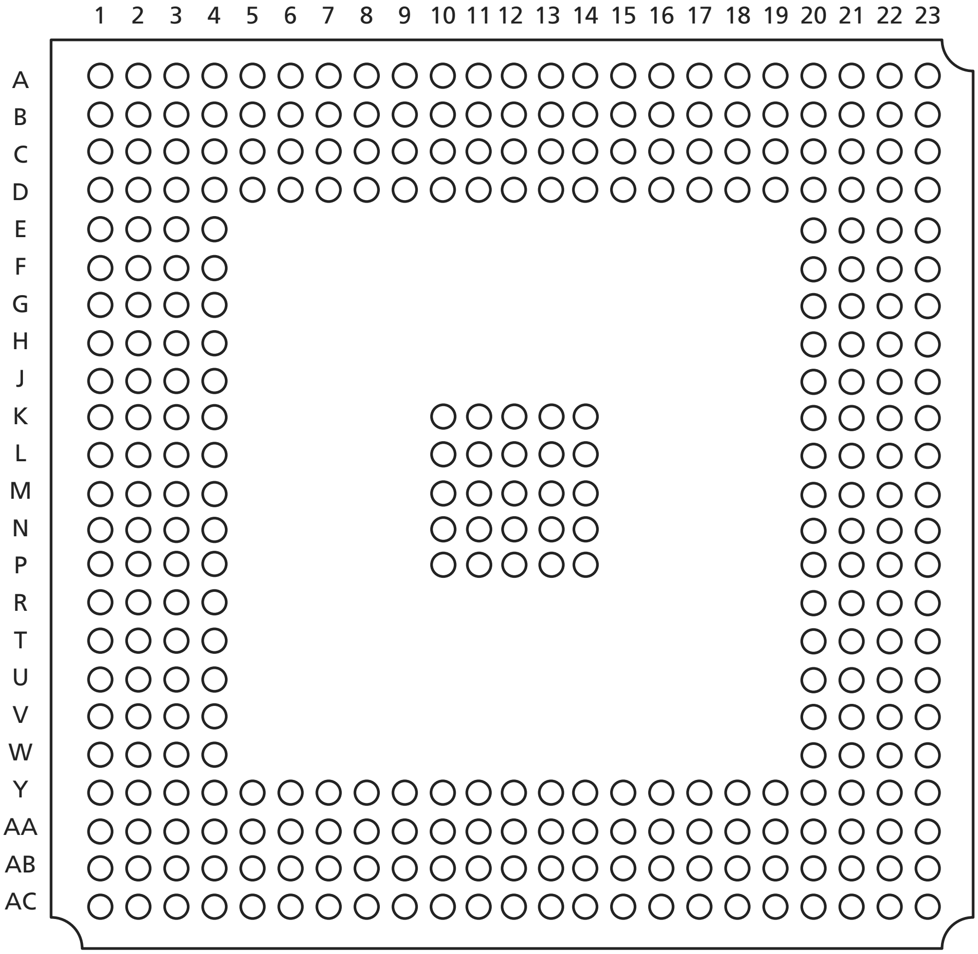


Figure 3-5 • **329-Pin PBGA (Top View)**

Note

For Package Manufacturing and Environmental information, visit Resource center at http://www.actel.com/products/rescenter/package/index.html.

256-Pin FBGA			
Pin Number	A54SX16A Function	A54SX32A Function	A54SX72A Function
K5	I/O	I/O	I/O
K6	V_{CCI}	V_{CCI}	V_{CCI}
K7	GND	GND	GND
K8	GND	GND	GND
K9	GND	GND	GND
K10	GND	GND	GND
K11	V_{CCI}	V_{CCI}	V_{CCI}
K12	I/O	I/O	I/O
K13	I/O	I/O	I/O
K14	I/O	I/O	I/O
K15	NC	I/O	I/O
K16	I/O	I/O	I/O
L1	I/O	I/O	I/O
L2	I/O	I/O	I/O
L3	I/O	I/O	I/O
L4	I/O	I/O	I/O
L5	I/O	I/O	I/O
L6	I/O	I/O	I/O
L7	V_{CCI}	V_{CCI}	V_{CCI}
L8	V_{CCI}	V_{CCI}	V_{CCI}
L9	V_{CCI}	V_{CCI}	V_{CCI}
L10	V_{CCI}	V_{CCI}	V_{CCI}
L11	I/O	I/O	I/O
L12	I/O	I/O	I/O
L13	I/O	I/O	I/O
L14	I/O	I/O	I/O
L15	I/O	I/O	I/O
L16	NC	I/O	I/O
M1	I/O	I/O	I/O
M2	I/O	I/O	I/O
M3	I/O	I/O	I/O
M4	I/O	I/O	I/O
M5	I/O	I/O	I/O
M6	I/O	I/O	I/O
M7	I/O	I/O	QCLKA
M8	PRB, I/O	PRB, I/O	PRB, I/O
M9	I/O	I/O	I/O

256-Pin FBGA			
Pin Number	A54SX16A Function	A54SX32A Function	A54SX72A Function
M10	I/O	I/O	I/O
M11	I/O	I/O	I/O
M12	NC	I/O	I/O
M13	I/O	I/O	I/O
M14	NC	I/O	I/O
M15	I/O	I/O	I/O
M16	I/O	I/O	I/O
N1	I/O	I/O	I/O
N2	I/O	I/O	I/O
N3	I/O	I/O	I/O
N4	I/O	I/O	I/O
N5	I/O	I/O	I/O
N6	I/O	I/O	I/O
N7	I/O	I/O	I/O
N8	I/O	I/O	I/O
N9	I/O	I/O	I/O
N10	I/O	I/O	I/O
N11	I/O	I/O	I/O
N12	I/O	I/O	I/O
N13	I/O	I/O	I/O
N14	I/O	I/O	I/O
N15	I/O	I/O	I/O
N16	I/O	I/O	I/O
P1	I/O	I/O	I/O
P2	GND	GND	GND
P3	I/O	I/O	I/O
P4	I/O	I/O	I/O
P5	NC	I/O	I/O
P6	I/O	I/O	I/O
P7	I/O	I/O	I/O
P8	I/O	I/O	I/O
P9	I/O	I/O	I/O
P10	NC	I/O	I/O
P11	I/O	I/O	I/O
P12	I/O	I/O	I/O
P13	V_{CCA}	V_{CCA}	V_{CCA}
P14	I/O	I/O	I/O

484-Pin FBGA		
Pin Number	**A54SX32A Function**	**A54SX72A Function**
K10	GND	GND
K11	GND	GND
K12	GND	GND
K13	GND	GND
K14	GND	GND
K15	GND	GND
K16	GND	GND
K17	GND	GND
K22	I/O	I/O
K23	I/O	I/O
K24	NC*	NC
K25	NC*	I/O
K26	NC*	I/O
L1	NC*	I/O
L2	NC*	I/O
L3	I/O	I/O
L4	I/O	I/O
L5	I/O	I/O
L10	GND	GND
L11	GND	GND
L12	GND	GND
L13	GND	GND
L14	GND	GND
L15	GND	GND
L16	GND	GND
L17	GND	GND
L22	I/O	I/O
L23	I/O	I/O
L24	I/O	I/O
L25	I/O	I/O
L26	I/O	I/O
M1	NC*	NC
M2	I/O	I/O
M3	I/O	I/O
M4	I/O	I/O
M5	I/O	I/O
M10	GND	GND
M11	GND	GND
M12	GND	GND
M13	GND	GND
M14	GND	GND
M15	GND	GND
M16	GND	GND
M17	GND	GND
M22	I/O	I/O
M23	I/O	I/O
M24	I/O	I/O
M25	NC*	I/O
M26	NC*	I/O
N1	I/O	I/O
N2	V_{CCI}	V_{CCI}
N3	I/O	I/O
N4	I/O	I/O
N5	I/O	I/O
N10	GND	GND
N11	GND	GND
N12	GND	GND
N13	GND	GND
N14	GND	GND
N15	GND	GND
N16	GND	GND
N17	GND	GND
N22	V_{CCA}	V_{CCA}
N23	I/O	I/O
N24	I/O	I/O
N25	I/O	I/O
N26	NC*	NC
P1	NC*	I/O
P2	NC*	I/O
P3	I/O	I/O
P4	I/O	I/O
P5	V_{CCA}	V_{CCA}
P10	GND	GND
P11	GND	GND
P12	GND	GND
P13	GND	GND
P14	GND	GND
P15	GND	GND
P16	GND	GND
P17	GND	GND
P22	I/O	I/O
P23	I/O	I/O
P24	V_{CCI}	V_{CCI}
P25	I/O	I/O
P26	I/O	I/O
R1	NC*	I/O
R2	NC*	I/O
R3	I/O	I/O
R4	I/O	I/O
R5	TRST, I/O	TRST, I/O
R10	GND	GND
R11	GND	GND
R12	GND	GND
R13	GND	GND
R14	GND	GND
R15	GND	GND
R16	GND	GND
R17	GND	GND
R22	I/O	I/O
R23	I/O	I/O
R24	I/O	I/O
R25	NC*	I/O
R26	NC*	I/O
T1	NC*	I/O
T2	NC*	I/O

Note: **These pins must be left floating on the A54SX32A device.*